New Course Code	MS7320: Physical Analysis of Materials
and Title	(2AU)
Course	AP Oh Joo Tien
Coordinator	
Details of Course	Rationale for introducing this course
Coordinator Details of Course	Rationale for introducing this course         Physical characterisation of materials is the measurement and evaluation of the properties of materials. It is essential for the development of materials, for materials failure investigation and routine assessment. Thermal analysis constituted a group of characterisation techniques in which the thermal properties of materials are characterised. Materials in service are subjected to extreme and fluctuating temperature conditions. As the properties and performance of materials are intimately related to the temperature, a group of thermal analysis techniques covering TGA, DSC, DTA, TMA etc in which the physical properties of materials are measured as a function of temperature whilst the material is subjected to a controlled temperature are employed to characterise materials.         Surface analysis is the study of the surface properties of materials. It is concerned with the study of the structure and binding state of the atoms on the top surface layer (< 10 nanometers). Surface Analysis are routine activities of surface inspection and is employed extensively in areas of research such as corrosion, adhesion, polymer surface treatment and microelectronics fabrication         It is therefore important that the materials engineer be exposed to these characterisation techniques.         This course introduces thermal analysis and surface analysis techniques to the materials engineer. In the module on thermal analysis, specific characterisation techniques will be covered in depth including Thermogravimetric analysis (TGA), Differential scanning calorimetry (DSC) and Differential Thermal Analysis (DTA). Other less common but advanced thermal techniques will also be introduced briefly. In the module on surface analysis, the course will be focussed on X-ray Photoelectron Spectroscopy (XPS) and Auger Electron Spectroscopy (AES).
	<ul> <li>thermal and surface analysis, for the investigation of material performance</li> <li>Develop laboratory facilities for thermal and surface analysis</li> </ul>
	Develop laboratory facilities for thermal and surface analysis
	Course Syllabus Refer to Page 3 to 4

Assessment	Assessment Points	3		
(Individual	Mode of Assessments and			
Assessment)	weighting	CA1: MCQs	30%	
		CA2: MCQs	30%	
		CA3: Project	40%	
			100%	
	Instructions			
		CA1: Open book, Randomised Questions and	Options	
		CA2: Open book, Randomised Questions and	Options	
		presented with a material and the properties of	ne wishes	
		to analyse.		
	Mapping of assessment to			
	course objectives	CA1 : LO1 and LO2		
	• I O1 · Select and	CA2: LO1 and LO2 CA3: LO1 and LO2		
	evaluate physical			
	characterisation			
	techniques, namely			
	analysis, for the			
	investigation of material			
	performance			
	LO2: Develop			
	laboratory facilities for			
	thermal and surface			
	allalysis			
To be offered with	AY2018/19 Semester 1			
effect from				
(state Academic				
Year and Somestor)				
Gemester				
Cross Listing (if	N/A			
applicable)				
Prerequisites (if	N/A			
Preclusions (if	Ν/Δ			
applicable)	/ V// \			
Mode of Teaching	Lectures, expert interviews	, MCQ, tutorials, authentic texts, peer discu	ssion	
& Learning		· · · · · ·		
(Lectures, regular				
tests, Q&A,				
learning)				
Basic Reading	Compulsory Reading:			
List				
Compulsory	1)Thermal Methods (Analy	tical Chemistry by Open Learning)		
Reading	(1987) James W. Dodd, Kenneth H. Tonge			
Supplementary	John Wiley & Sons			
Reading				

	<ul> <li>2) Introduction to Surface Analysis by Electron Spectroscopy</li> <li>(1990) John F. Watts</li> <li>Oxford Science Publications</li> </ul>
	<b>Supplementary Reading</b> Thermal Methods of Analysis: Principles, Applications and Problems. (1995) by Peter J Haines Thermal Methods
	Introduction to Surface Analysis by XPS and AES John Watts and John Wolstenholme John Wiley (2005)
Hours of Contact/Academic Units	26 hours/ 2 AU

## Course Syllabus

The following topics will be covered:

## Module 1: Thermal Analysis of Materials

- 1. Introduction to Thermal Analysis Introduction to thermal analysis and thermal methods. The basic principle behind thermal analysis and introduces the use of thermal analysis in industry and research.
- Thermogravimetry and Differential Thermogravimetry The concept of mass loss and enthalpy change in materials during. The TG and DTA/DCS curve. Exotherm and endotherm.
- Instrumentation and Experimental Procedure for TG/DTG Instrumentation for TG and DTG. Description of the critical components for TG and DTG experiments. Experimental procedure.
- 4. Interpretation of TG and DTG curves Interpretation of TG/DTG curves. Quantitative and qualitative treatment in decomposition process.
- Differential Thermal Analysis (DTA) and Differential Scanning Calorimetry (DSC) Instrumentation and Experimental Procedure Difference between DTA and DCS instrumentation. Instrumentation. Determination of enthalpy of reaction in DTA. Procedural temperatures and experimental factors
- Differential Thermal Analysis (DTA) and Differential Scanning Calorimetry (DSC) Interpretations and Applications Interpretation of DTA/DSC curves. Examples in food processing, research, pharmaceuticals, forensic, textile industries.
- Multiple Techniques
   Types of multiple techniques in thermal analysis. Application of multiple thermal analysis techniques
   in materials characterisation. Combining TG with DTA/DSC, TG/Hot stage microscopy, DSC/TMA.

## Module 2: Surface Analysis of Materials

- 1. Introduction to Surface Analysis Introduction to surface analysis and requirement of ultra-low pressure. High vacuum pumping system.
- Spectroscopy Electromagnetic radiation interaction with matter. Types of transitions, rotational, vibrational and electronic. Types of spectroscopy
- Principle of X-ray Photoelectron spectroscopy, Instrumentation (XPS) Photoelectric effect, High energy spectroscopy, concept of photoelectron spectroscopy, X-ray photoelectron spectroscopy (XPS).
- X-ray Photoelectron Spectroscopy, Interpretation of XPS spectrum XPS instrumentation. Spin-Orbit coupling, total angular momentum and Siegbahn notation for assigning XPS peaks.
- 5. Principle of Auger Electron Spectroscopy (AES) and Instrumentation Auger effect, auger electron spectroscopy, instrumentation and AES techniques
- 6. Interpretation of Electron Spectrum from XPS and AES Identification of elements, binding state and quantification. Compositional depth profiling
- Application of XPS and AES in Materials Science Applications in metallurgy, corrosion science, ceramic materials, polymers, microelectronics and adhesion science.
- Other Surface Analysis Techniques Secondary ions spectroscopy (SIMS), Scanning Tunnelling Microscopy (STM), Atomic Force Microscopy (AFM) and Field Ion Microscopy (FIM).